

**Notice of References Cited**

Application/Control No.

09/661,223

Applicant(s)/Patent Under  
Reexamination  
KAIBUKI, FUTOSHI

Examiner

Kim T. Huynh

Art Unit

2189

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-20030210252	11-2003	Ludtke et al.	345/629
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
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